PCN Number: 2023)230327007.1 P		PCN Date:			March 30, 2023	
Title	٥:	Qualification of	of ne	w Fa	v Fab site (RFAB) using qualified Process Technology, Die Revision,				
Title	С.	Datasheet and	d add	lition	al Assembly site/BO	M options t	or se	lect dev	vices
Cus	tomer	Contact:	<u>P</u>	CN N	<u>lanager</u>	Dept:			Quality Services
Proposed 1 st Ship Date:						Sample requests accepted until:		Apr 30, 2023*	
*Sa	*Sample requests received after April 30, 2023 will not be supported.								
Cha	nge Ty	/pe:							
\boxtimes	Assen	nbly Site			Assembly Process		M	Assembly Materials	
\boxtimes	Desigi	n		M	Electrical Specification			Mechanical Specification	
	Test S	Site		X	Packing/Shipping/Labeling			Test Process	
☐ Wafer Bump Site				Wafer Bump Mater	ial		Wafer Bump Process		
			X	Wafer Fab Materials		\boxtimes	Wafer Fab Process		
					☐ Part number change				
	PCN Details								

Description of Change:

Texas Instruments is pleased to announce the qualification of a new fab & process technology (RFAB, LBC7) and HFTF and TI Malaysia as additional Assembly sites for selected devices listed below in the product affected section.

С	urrent Fab Site		Additional Fab Site			
Current Fab Process Wafer Diameter		Additional Fab Site	Wafer Diameter			
DL-LIN	LBC3S	150 mm	RFAB	LBC7	300 mm	
DL-LIN	LBC3S	200 mm	KFAD	LBC/	300 11111	

The die was also changed as a result of the process change.

Assembly BOM options are noted below:

	FMX	MLA	TAI	UTL2	HFTFAT	MLA (new)
Mold Compound	4211880	4211880	4211880	SID#CZ0094	SID#R-30	4211880
Bond wire composition, diameter	Cu, 0.96	Cu, 0.8 or Au, 0.96 mil	Cu, 0.96	Au, 1.0 mil	Cu, 1.0 mil	Cu, 0.96
Mount Compound	4147858	4147858	4147858	SID#PZ0013	SID#A-18	4147858
Lead finish	NiPdAu	NiPdAu	NiPdAu	NiPdAu	Matte Sn	NiPdAu

Upon expiry of this PCN TI will combine lead free solutions in a single <u>standard part number</u>. For example; <u>SN65HVD3086EDR</u> – can ship with both Matte Sn and NiPdAu/Ag.

Example:

- Customer order for 7500 units of SN65HVD3086EDR with 2500 units SPQ (Standard Pack Quantity per Reel).
- TI can satisfy the above order in one of the following ways.
 - I. 3 Reels of NiPdAu finish.
 - II. 3 Reels of Matte Sn finish
 - III. 2 Reels of Matte Sn and 1 reel of NiPdAu finish.
 - IV. 2 Reels of NiPdAu and 1 reel of Matte Sn finish.

The datasheet will be changing as a result of the above mentioned changes. The datasheet change details can be reviewed in the datasheet revision history. The links to the revised datasheets are available in the table below.

SN75HVD05, SN75HVD06, SN75HVD07 SN65HVD05, SN65HVD06, SN65HVD07

SLLS533F - MAY 2002 - REVISED MARCH 2023

Changes from Revision E (August 2009) to Revision F	(March 2023) Pa	ige
Deleted the Ordering Information table		1
Added the Thermal Information table		
Changed the Typical Characteristics		9
		_
TEXAS	SN75HVD08, SN65HVI	
INSTRUMENTS	SLLS550E – NOVEMBER 2002 – REVISED MARCH 2	2023
Changes from Revision D (March 2015) to Revision E (age
Changed the Thermal Information table		4
Changed the Typical Characteristics		7
₹ ia Texas	SN65HVD50, SN65HVD51, SN65HVD	
INSTRUMENTS	SN65HVD53, SN65HVD54, SN65HVD	
- INSTROMENTS	SLLS666F – SEPTEMBER 2005 – REVISED MARCH 2	2023
Changes from Revision E (October 2009) to Revision F	(March 2023) Pa	age
Changed the Thermal Characteristics table		.11
Changed the Typical Characteristics		. 12
Bio Theorem		_
TEXAS INSTRUMENTS	SN65HVD3080E, SN65HVD3083E, SN65HVD308	
INSTRUMENTS	SLLS771F – NOVEMBER 2006 – REVISED MARCH 2	023
Changes from Revision E (November 2012) to Revision	F (March 2023) Pa	age
Deleted the Ordering Information table		1
Added the Device Information table		1
Added the Thermal Information table		
Changed the Typical Characteristics		7

Product Folder	Current Datasheet Number	New Datasheet Number	Link to full datasheet		
SN65HVD0x, SN75HVD0x	SLLS533E	SLLS533F	http://www.ti.com/product/SN65HVD05		
SNx5HVD08	SLLS550D	SLLS550E	http://www.ti.com/product/SN65HVD08		
SN65HVD5x	SLLS666E	SLLS666F	http://www.ti.com/product/SN65HVD50		
SN65HVD308xE	SLLS771E	SLLS771F	http://www.ti.com/product/SN65HVD3080E		

Tube and temperature variants of the devices are included in EOL notice PDN# 20230327009.3.

Qual details are provided in the Qual Data Section.

Reason for Change:

These changes are part of our multiyear plan to transition products from our 150-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings:

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	Green Status	IEC 62474
No Change	No Change	☑ No Change	No Change ■

Changes to product identification resulting from this PCN:

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City	
DL-LIN	DLN	USA	Dallas	
RFAB	RFB	USA	Richardson	

Die Rev:

Current New

Die Rev [2P]	Die Rev [2P]
Α	В

Assembly Site Information:

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City	
FMX	MEX	MEX	Aguascalientes	
MLA	MLA	MYS	Kuala Lumpur	
TAI	TAI	TWN	Chung Ho, New Taipei City	
UTL2	NS2	THA	Bangpakong, Chachoengsao	
HFTF	HFT	CHN	Hefei	

Sample product shipping label (not actual product label)

TEXAS INSTRUMENTS
MADE IN: Malaysia 2DC: 20:

MSL '2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04

OPT: ITEM:

: 5A (L)TO:1750



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812 (P) (2P) PEV: (V) 0033317

(2P) REV: (V) 0033317 (20L) 698. SHE (21L) CCO-USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected:

SN65HVD05DR	SN65HVD08DRG4	SN65HVD3086EDGSR	SN65HVD52DR
SN65HVD06DR	SN65HVD3080EDGSR	SN65HVD3086EDR	SN65HVD53DR
SN65HVD07DR	SN65HVD3083EDGSR	SN65HVD50DR	SN65HVD55DR
SN65HVD08DR			

For alternate parts with similar or improved performance, please visit the product page on II.com

Qualification Report Approve Date 02-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: SN65HVD05DR	QBS Reference: TCAN1044VDRQ1	QBS Reference: TCAN1044VDRQ1	QBS Reference: TPS51217DSCR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	1/77/0	2/154/0	3/231/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	1/77/0	2/154/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	1/77/0	2/154/0	3/231/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	3/231/0
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	1/45/0	2/90/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	1/77/0	2/154/0	-
HTOL	B1	Life Test	135C	635 Hours	-	-	-	3/231/0
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	-	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	1/10/0	2/20/0	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	3/9/0
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	-	-	3/9/0
ESD	E2	ESD HBM (Bus Pins)	-	16000 Volts	1/3/0	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	3/18/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	3/60/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	2/60/0	-	-
FTY	E6	Final Test Yield	-	-	1/1/0	-	-	-

- QBS: Qual By Similarity
- Qual Device SN65HVD05DR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: SN65HVD06DR	Qual Device: SN65HVD07DR	QBS Reference: TCAN1044VDRQ1	QBS Reference: TCAN1044VDRQ1	QBS Reference: TPS51217DSCR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	1/77/0	2/154/0	3/231/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	1/77/0	2/154/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	1/77/0	2/154/0	3/231/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	-	3/231/0
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	1/45/0	2/90/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	1/77/0	2/154/0	-
HTOL	B1	Life Test	135C	635 Hours	-	-	-	-	3/231/0
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	1/76/0	-	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	1/76/0	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-
SD	СЗ	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	1/10/0	2/20/0	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	1/3/0	-	-	3/9/0
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	1/3/0	-	-	3/9/0
ESD	E2	ESD HBM (Bus Pins)	-	16000 Volts	1/3/0	1/3/0	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	1/3/0	-	-	3/18/0
CHAR	R E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	-	3/60/0
CHAR	R E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	2/60/0	-	-
FTY	E6	Final Test Yield	-	-	1/1/0	1/1/0	-	-	-

- QBS: Qual By Similarity
- Qual Device SN65HVD06DR is qualified at MSL1 260C
- Qual Device SN65HVD07DR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: SN65HVD50DR	Qual Device: SN65HVD53DR	QBS Reference: TCAN1044VDRQ1	QBS Reference: TCAN1044VDRQ1	QBS Reference: TPS51217DSCR	QBS Reference: TCAN1043DQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	1/77/0	2/154/0	3/231/0	3/231/0
UHAST	А3	Autoclave	121C/15psig	96 Hours	-	-	1/77/0	2/154/0	3/231/0	3/231/0
тс	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	1/77/0	2/154/0	3/231/0	3/231/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	-	3/231/0	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	1/45/0	2/90/0	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	1/77/0	2/154/0	-	1/77/0
HTOL	B1	Life Test	135C	635 Hours	-	-	-	-	3/231/0	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	1/76/0	-	-	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	1/76/0	-	-	-	-

SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-	1/15/0
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-	1/15/0
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	1/10/0	2/20/0	-	3/30/0
ESD	E2	ESD CDM	-	250 Volts	1/3/0	1/3/0	-	-	3/9/0	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	1/3/0	-	-	3/9/0	-
ESD	E2	ESD HBM (Bus Pins)	-	16000 Volts	1/3/0	1/3/0	-	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	1/3/0	-	-	3/18/0	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	3/60/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	2/60/0	-	-	1/30/0
FTY	E6	Final Test Yield	-	-	1/1/0	1/1/0	-	-	-	-

- QBS: Qual By Similarity
- Qual Device SN65HVD50DR is qualified at MSL1 260C
- Qual Device SN65HVD53DR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualification Report Approve Date 27-FEBRUARY -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: SN65HVD08DR	QBS Reference: TCAN1044VDRQ1	QBS Reference: TCAN1044VDRQ1	QBS Reference: TPS51217DSCR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	1/77/0	2/154/0	3/231/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	1/77/0	2/154/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	1/77/0	2/154/0	3/231/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	3/231/0
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	1/45/0	2/90/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	1/77/0	2/154/0	-
HTOL	B1	Life Test	135C	635 Hours	-	-	-	3/231/0
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	-	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-
DD.		Dhi I Dii	C-10 4 C7			4400	2/20/0	

PD	C4	Physical Dimensions	Cpk>1.67	-	-	1/10/0	2/20/0	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	3/9/0
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	-	-	3/9/0
ESD	E2	ESD HBM (Bus Pins)	-	16000 Volts	1/3/0	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	3/18/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	3/60/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	2/60/0	-	-
FTY	E6	Final Test Yield	-	-	1/1/0	-	-	-

- QBS: Qual By Similarity
- Qual Device SN65HVD08DR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре		Test Name	Condition	Duration	Qual Device: SN65HVD3086EDR	Qual Device: SN6SHVD3080EDGSR	Qual Device: SN65HVD3083EDGSR	Qual Device: SN65HVD3086EDGSR	QBS Reference: TPS51217DSCR	QBS Reference: TCAN1043DQ1	QBS Reference: SN65HVD3085EDR	QBS Reference: SN65HVD3085EDGKR	QBS Reference: SN65HVD3088EDR	QBS Reference: SN65HVD3088EDGKR
HAST	AZ	Blased HAST	130C/85%RH	96 Hours	-		-		3/231/0	3/231/0	-			
UHAST	A3	Autoclave	121C/15psig	96 Hours		1/77/0			3/231/0	3/231/0				
тс	A4	Temperature Cycle	-65C/150C	500 Cycles		1/77/0			3/231/0	3/231/0				
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-		3/231/0	-	-	-		
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-		1/45/0	-	-	-	-
HTOL	81	Life Test	125C	1000 Hours	-		-		-	1/77/0	-	-		
HTOL	81	Life Test	135C	635 Hours			-		3/231/0	-	-			-
WBS	Cl	Ball Shear	76 balls, 3 units min	Wires	1/76/0	1/76/0	1/76/0			-	1/76/0	1/76/0	1/76/0	1/76/0
WEP	CZ	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	1/76/0	1/76/0	1/76/0	-	-	1/76/0	1/76/0	1/76/0	1/76/0
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)						-	1/15/0			-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)		-					1/15/0			-	
PD	C4	Physical Dimensions	Cpic>1.67							3/30/0				
ESD	E2	ESD CDM		1500 Volts	-		-		3/9/0	-	1/3/0	1/3/0	1/3/0	1/3/0
ESD	E2	ESD CDM		250 Volts	1/3/0	1/3/0	1/3/0	1/3/0	-	-	-			
ESD	E2	ESD HBM		1000 Volts	1/3/0	1/3/0	1/3/0		-	-				
ESD	E2	ESD HBM (Bus Pins)		12000 Volts	1/3/0	1/3/0	1/3/0		-	-	-	-		-
ESD	EZ	ESD HBM (Bus Pins)		15000 Volts	-	-	-	-	-	-	1/3/0	-	1/3/0	-
ESD	EZ	ESD HBM		2000 Volts	-		-		3/9/0		-		-	
ESD	EZ	ESD HBM		4000 Volts	-	-	-		-	-	1/3/0	-	1/3/0	-
LU	E4	Letch-Up	Per JESD78		1/3/0	1/3/0	1/3/0		3/18/0		1/6/0		1/6/0	
CHAR	E5	Electrical Characterization	Per Datasheet Parameters		1/30/0	1/30/0	1/30/0		3/60/0		1/30/0		1/30/0	
CHAR	ES	Electrical Distributions	Cpi>1.67 Room, hot, and cold				-			1/30/0				
FTY	E6	Final Test Yield			1/1/0	1/1/0	1/1/0	1/1/0						

- QBS: Qual By Similarity
 Qual Device SN65HVD3086EDR is qualified at MSL1 260C
 Qual Device SN65HVD3080EDGSR is qualified at MSL1 260C
 Qual Device SN65HVD308DGSR is qualified at MSL1 260C
 Qual Device SN65HVD3086EDGSR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
 The following are equivalent HTCL options based on an activation energy of 0.7eV: 125C/Ik Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
 The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/Ik Hours, and 170C/420 Hours
 The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: SN65HVD52DR	Qual Device: SN65HVD55DR	QBS Reference: TCAN1044VDRQ1	QBS Reference: TCAN1044VDRQ1	QBS Reference: TPS51217DSCR	QBS Reference: <u>TCAN1043DQ1</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	1/77/0	2/154/0	3/231/0	3/231/0
UHAST	А3	Autoclave	121C/15psig	96 Hours	-	-	1/77/0	2/154/0	3/231/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	1/77/0	2/154/0	3/231/0	3/231/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	-	3/231/0	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	1/45/0	2/90/0	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	1/77/0	2/154/0	-	1/77/0
HTOL	B1	Life Test	135C	635 Hours	-	-	-	-	3/231/0	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	1/76/0	-	-	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	1/76/0	-	-	-	-
SD	СЗ	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-	1/15/0
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-	1/15/0
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	1/10/0	2/20/0	-	3/30/0
ESD	E2	ESD CDM	-	250 Volts	1/3/0	1/3/0	-	-	3/9/0	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	1/3/0	-	-	3/9/0	-
ESD	E2	ESD HBM (Bus Pins)	-	16000 Volts	1/3/0	1/3/0	-	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	1/3/0	-	-	3/18/0	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	3/60/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	2/60/0	-	-	1/30/0
FTY	E6	Final Test Yield	-	-	1/1/0	1/1/0	-	-	-	-

- QBS: Qual By Similarity
- Qual Device SN65HVD52DR is qualified at MSL1 260C
- Qual Device SN65HVD55DR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- $\bullet \quad \text{The following are equivalent HTSL options based on an activation energy of 0.7eV: } 150\text{C/1k Hours, and } 170\text{C/420 Hours}$
- $\bullet \quad \text{The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles}\\$

Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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